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- **Qualification in Accordance With** AEC-Q100†
- **Qualified for Automotive Applications**
- **Customer-Specific Configuration Control** Can Be Supported Along With Major-Change Approval
- **ESD Protection Exceeds 1500 V Per** MIL-STD-883. Method 3015: Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Wide Operating Voltage Range of 2 V to 6 V
- **Outputs Can Drive Up To 10 LSTTL Loads**
- Low Power Consumption, 80-µA Max ICC
- Typical  $t_{pd} = 13 \text{ ns}$
- ±4-mA Output Drive at 5 V
- Low Input Current of 1 µA Max
- **Complementary Outputs**
- **Direct Overriding Load (Data) Inputs**
- **Gated Clock Inputs**
- Parallel-to-Serial Data Conversion

#### D OR PW PACKAGE (TOP VIEW) 16**[**] V<sub>CC</sub> SH/LD 15 CLK INH CLK [ E **∏** 3 14 D F ∏ 4 13**∏** C G 🛮 5 12 B 11 🛮 A Н Q<sub>H</sub> [] 7 10 SER 9 🕽 Q<sub>H</sub> GND [] 8

## description/ordering information

The SN74HC165 is an 8-bit parallel-load shift register that, when clocked, shift the data toward a serial (Q<sub>H</sub>) output. Parallel-in access to each stage is provided by eight individual direct data (A-H) inputs that are enabled by a low level at the shift/load (SH/LD) input. The SN74HC165 also features a clock-inhibit (CLK INH) function and a complementary serial  $(\overline{\mathbb{Q}}_{H})$  output.

Clocking is accomplished by a low-to-high transition of the clock (CLK) input while SH/LD is held high and CLK INH is held low. The functions of CLK and CLK INH are interchangeable. Since a low CLK and a low-to-high transition of CLK INH also accomplish clocking, CLK INH should be changed to the high level only while CLK is high. Parallel loading is inhibited when SH/LD is held high. While SH/LD is low, the parallel inputs to the register are enabled independently of the levels of the CLK, CLK INH, or serial (SER) inputs.

#### ORDERING INFORMATION

TA	PACKAGE‡		ORDERABLE PART NUMBER	TOP-SIDE MARKING
400C to 4050C	SOIC - D	Tape and reel	SN74HC165QDRQ1	HC165Q1
-40°C to 125°C	TSSOP - PW	Tape and reel	SN74HC165QPWRQ1	HC165Q1

<sup>‡</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



<sup>†</sup> Contact factory for details. Q100 qualification data available on request.

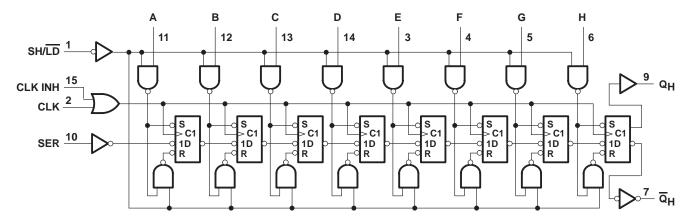
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#### **FUNCTION TABLE**

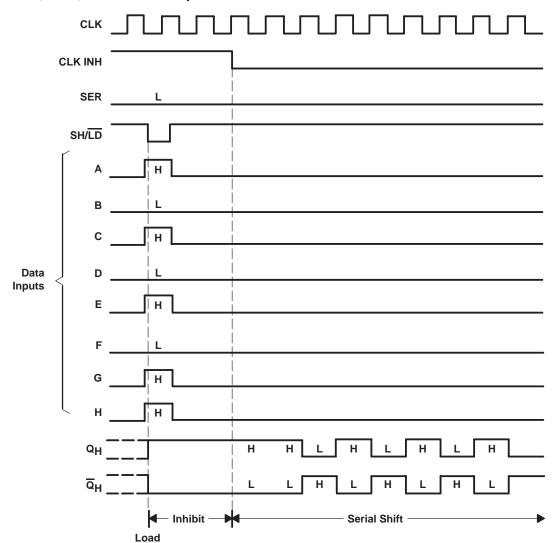
	INPUT	S	
SH/LD	CLK	CLK INH	FUNCTION
L	Χ	Х	Parallel load
Н	Н	Χ	No change
Н	Χ	Н	No change
Н	L	$\uparrow$	Shift <sup>†</sup>
Н	$\uparrow$	L	Shift <sup>†</sup>

<sup>†</sup>Shift = content of each internal register shifts toward serial output Q<sub>H</sub>. Data at SER is shifted into the first register.

### logic diagram (positive logic)



## typical shift, load, and inhibit sequence



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub>	$\dots$ $-0.5\ V$ to 7 $V$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	73°C/W
PW package	108°C/W
Storage temperature range, T <sub>Sto</sub>	65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### recommended operating conditions (see Note 3)

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			
$\vee_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			V
		V <sub>CC</sub> = 6 V	4.2			
VIL		V <sub>CC</sub> = 2 V			0.5	
	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35	V
		V <sub>CC</sub> = 6 V			1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	V
VO	Output voltage		0		VCC	V
		V <sub>CC</sub> = 2 V			1000	
Δt/Δv <sup>‡</sup>	Input transition rise/fall time	V <sub>CC</sub> = 4.5 V			500	ns
	V <sub>CC</sub> = 6 V			400		
TA	Operating free-air temperature		-40		125	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51-7.

<sup>‡</sup> If this device is used in the threshold region (from VII max = 0.5 V to VIHmin = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t<sub>t</sub> = 1000 ns and V<sub>CC</sub> = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

## SN74HC165-Q1 8-BIT PARALLEL-LOAD SHIFT REGISTER

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

242445752	7507.001	UDITIONS	.,	Т	A = 25°C	;			
PARAMETER	TEST CON	NDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		
		$I_{OH} = -20  \mu A$	4.5 V	4.4	4.499		4.4		
∨он	VI = VIH or VIL		6 V	5.9	5.999		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		
			2 V		0.002	0.1		0.1	
		$I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1	
VoL	$V_I = V_{IH}$ or $V_{IL}$		6 V		0.001	0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4	
		$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4	
l <sub>l</sub>	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000	nA
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160	μΑ
Ci			2 V to 6 V		3	10	_	10	pF

## SN74HC165-Q1 8-BIT PARALLEL-LOAD SHIFT REGISTER

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# timing requirements over recommended operating free-air temperature range (unless otherwise noted)

				T <sub>A</sub> =	25°C			
			VCC	MIN	MAX	MIN	MAX	UNIT
			2 V		6		4.2	
fclock	Clock frequency		4.5 V		31		21	MHz
			6 V		36		25	
			2 V	80		120		
		SH/LD low	4.5 V	16		24		
	t <sub>W</sub> Pulse duration		6 V	14		20		
$t_W$			2 V	80		120		ns
		CLK high or low	4.5 V	16		24		
		6 V	14		20			
			2 V	80		120		
		SH/LD high before CLK↑	4.5 V	16		24		
			6 V	14		20		
			2 V	40		60		
		SER before CLK↑	4.5 V	8		12		
		6 V	7		10			
			2 V	100		150		
t <sub>su</sub>	Setup time	CLK INH low before CLK↑	4.5 V	20		30		ns
-	·		6 V	17		25		
			2 V	40		60		
		CLK INH high before CLK↑	4.5 V	8		12		
			6 V	7		10		
			2 V	100		150		
		Data before SH/ <del>LD</del> ↓	4.5 V	20		30		
			6 V	17		26		
			2 V	5		5		
		SER data after CLK↑	4.5 V	5		5		
4.	Hald time		6 V	5		5		
th	Hold time		2 V	5		5		ns
		PAR data after SH/LD↓	4.5 V	5		5		
			6 V	5		5		

## SN74HC165-Q1 8-BIT PARALLEL-LOAD SHIFT REGISTER

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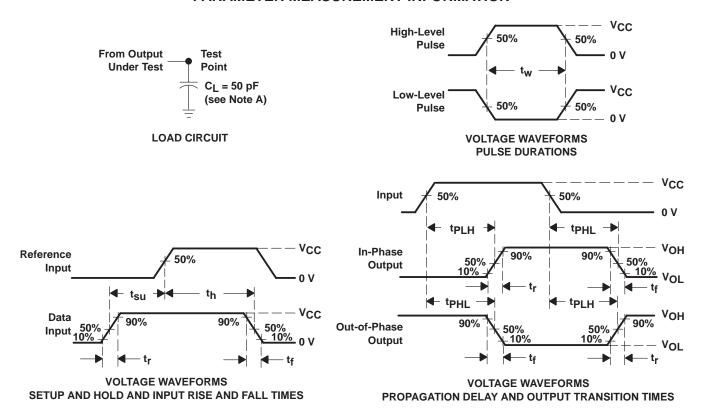
# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

	FROM	то	.,	T,	4 = 25°C	;			
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	6	13		4.2		
f <sub>max</sub>			4.5 V	31	50		21		MHz
			6 V	36	62		25		
			2 V		80	150		225	
	SH/LD	$Q_H$ or $\overline{Q}_H$	4.5 V		20	30		45	
			6 V		16	26		38	
			2 V		75	150		225	ns
<sup>t</sup> pd	CLK	$Q_H$ or $\overline{Q}_H$	4.5 V		15	30		45	
·			6 V		13	26		38	
			2 V		75	150		225	
	Н	$Q_H$ or $\overline{Q}_H$	4.5 V		15	30		45	
			6 V		13	26		38	
			2 V		38	75		110	
t <sub>t</sub>		Any	4.5 V		8	15		22	ns
			6 V		6	13		19	

## operating characteristics, $T_A = 25^{\circ}C$

		PARAMETER	TEST CONDITIONS	TYP	UNIT
ſ	C <sub>pd</sub>	Power dissipation capacitance	No load	75	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and test-fixture capacitance.

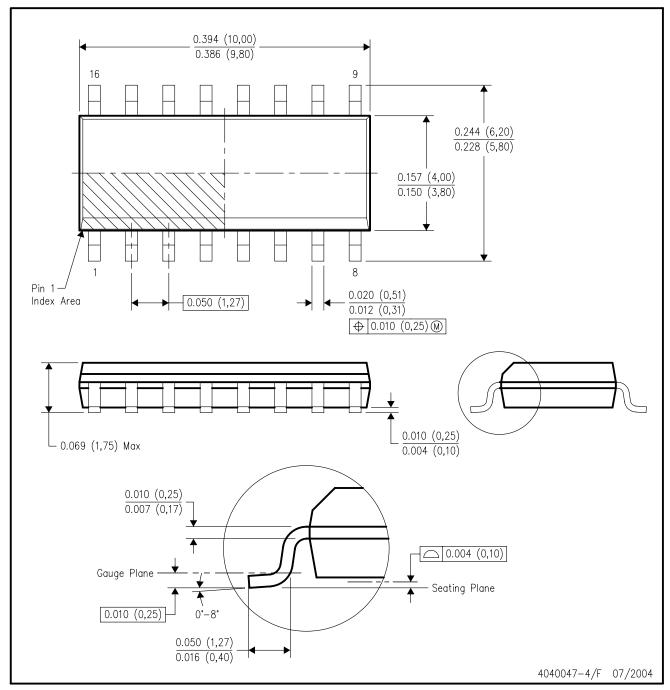
- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 6 \ ns$ ,  $t_f = 6 \ ns$ .
- C. For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



## D (R-PDSO-G16)

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012 variation AC.



### PW (R-PDSO-G\*\*)

#### 14 PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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